

Electrical and Thermal Conductivities of Single Cu_xO Nanowires

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Table S1. Rietveld refinement main parameters for the cuprite and tenorite crystals.

Cuprite					Tenorite							
9007497					9016105				9014580			
value					error		value		Error	value		error
Cell parameters	a	Å	4.2865	6 · 10 ⁻⁴	Cell parameters	a	Å	4.6998	1.3 · 10 ⁻³	4.5978	1.7 · 10 ⁻³	
	b	Å				b	Å	3.4274	9 · 10 ⁻⁴	3.3233	7 · 10 ⁻⁴	
	c	Å				c	Å	5.1501	1.4 · 10 ⁻³	5.850	1.2 · 10 ⁻³	
	α	°	90			β	°	99.389	1.3 · 10 ⁻²	99.500	1.7 · 10 ⁻²	
Crystalline size		Å	754	38	Crystalline size		Å	461	18	2530	20	
Microstrain			0.00310	9 · 10 ⁻⁵	Microstrain			0.00260	1.4 · 10 ⁻⁴	0.0035	2 · 10 ⁻⁴	
Density		g·cm ⁻³	6.0336		Density		g·cm ⁻³	6.4553				
Weight		± 0.9 %	44.2 %		Weight		± 0.9 %	55.8 %				

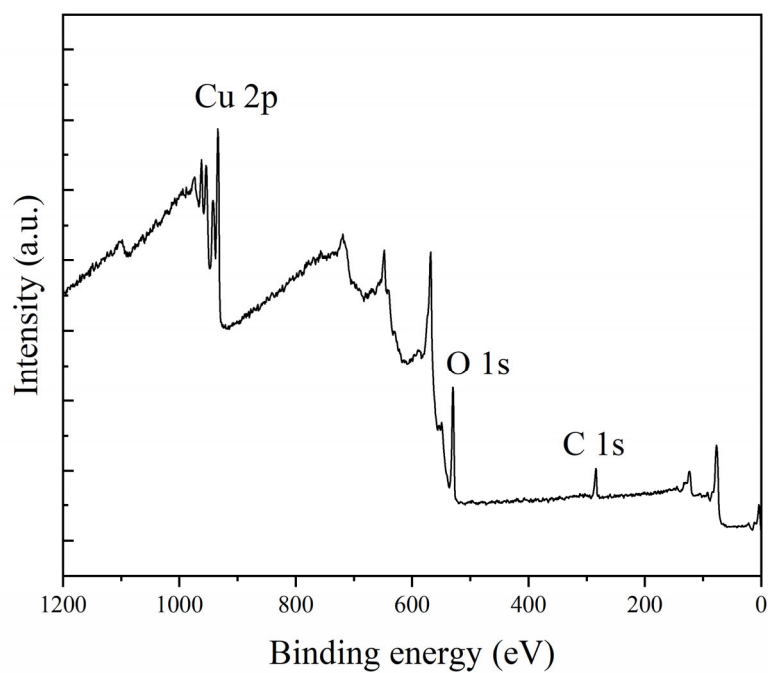


Figure S1. XPS survey scan of the NWs sample.

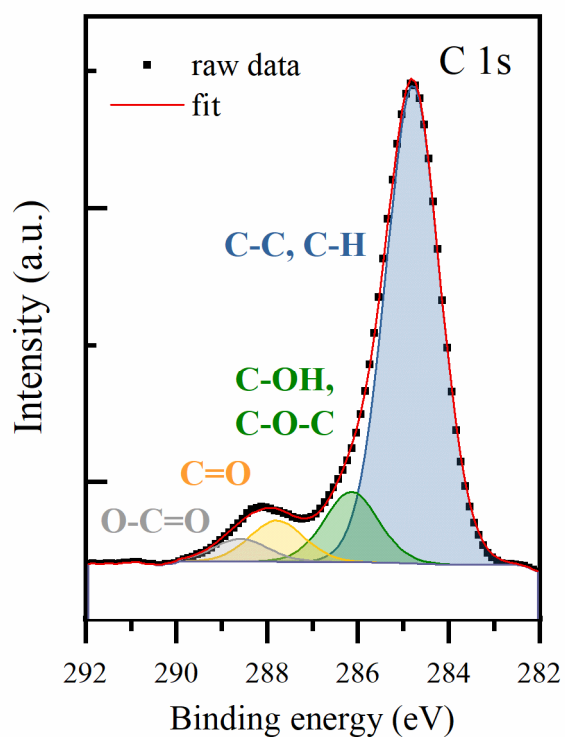


Figure S2. XPS HR scan of the C 1s region for calibration on the adventitious carbon, and deconvolution of the peak.